



Computational Sensing and Imaging II

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Message from the Guest Editor

Computational sensing and imaging play a major role in imaging techniques and have many applications in areas of medical imaging, 3D imaging, lensless imaging, synthetic aperture radar imaging, seismic imaging, ultrasound imaging, and so on. In addition, extensive research has accelerated the sensing and imaging performance of those applications in the last few years. Specifically, this Special Issue is focused on image processing to obtain high-quality images and to remedy various problems to deteriorate the sensing and imaging performance of physical or optical devices in terms of image quality, imaging speed, and functionality.

This Special Issue aims to broadly engage the communities of image processing and signal sensing to provide a forum for researchers and engineers related to this rapidly developing field, allowing them to share their novel and original research on the topic of computational sensing and imaging. Survey papers addressing relevant topics are also welcome.





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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